

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:)
Hidekazu MIYAIRI et al.) Group Art Unit: 1722
Serial No. 10/663,671) Examiner: Felisa Carla Hiteshew
Filed: September 17, 2003)
For: LASER APPARATUS, LASER IRRADIATION) Date: June 8, 2006
METHOD, AND MANUFACTURING METHOD
OF SEMICONDUCTOR DEVICE

INFORMATION DISCLOSURE STATEMENT

Mail Stop **Amendment**
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

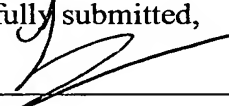
Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. §1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98

It is requested that the accompanying PTO-1449 be considered and made of record in the above-identified application. To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initial a copy of this form be returned to the undersigned.

The Commissioner is hereby authorized to charge any fees connected with this filing which may be required now, or credit any overpayment to Deposit Account No. 19-2380.

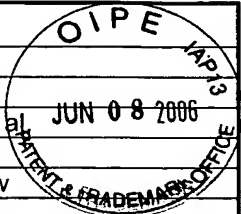
Respectfully submitted,



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Substitute for form 1449A/PTO			Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>			Application Number	10/663,671	
			Filing Date	September 17, 2003	
			First Named Inventor	Hidekazu MIYAIRI et al.	
			Group Art Unit	1722	
			Examiner Name	Felisa Carla Hiteshew	
Sheet	1	of	1	Attorney Docket Number	740756-2651



U.S. PATENT DOCUMENTS					
Examiner Initials [*]	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
	1	US-4,092,530	05-30-1978	Wise	
	2	US-5,157,676	10-20-1992	Wilcox	
	3	US-5,856,880	01-05-1999	Farina et al.	
	4	US-6,078,390	06-20-2000	Bengtsson	
	5	US-6,091,047	07-18-2000	Miyakawa et al.	
	6	US-6,707,031 B1	03-16-2004	Weinberger et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials [*]	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)				

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04.
³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.